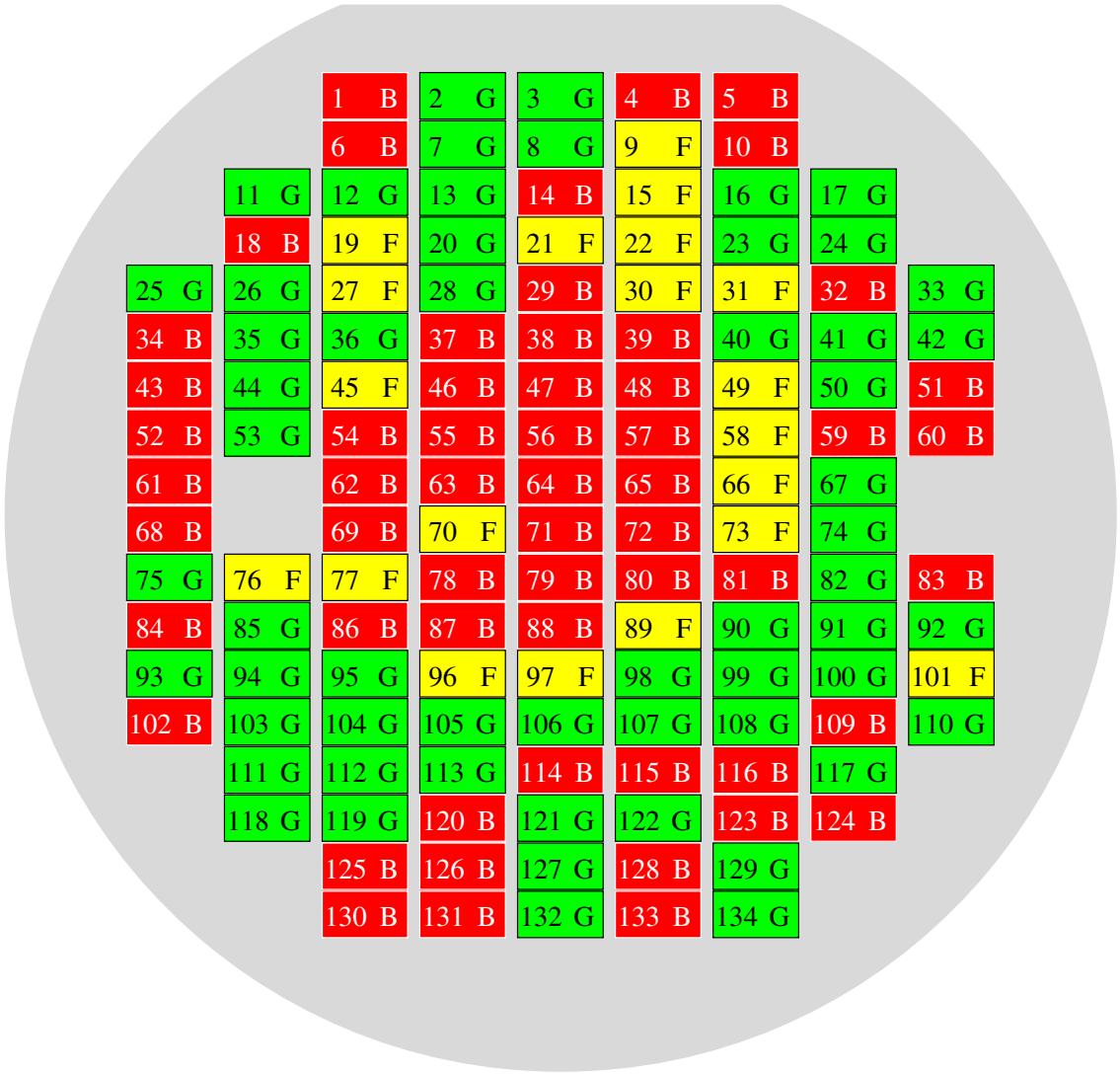
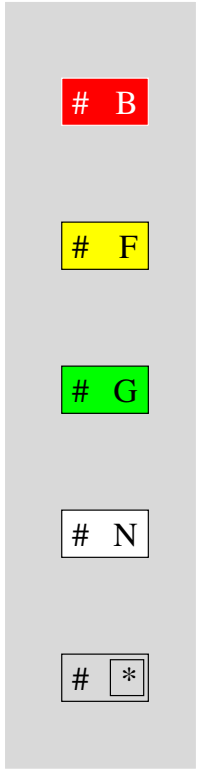
Die quality map for wafer 177 s/n: Y21316-09-06

Date: 07/08/99





Bad die

Fair die

Good die

No info

Manually tagged